INFORMATION DISCLOSURE

Atty. Docket No.: 153.0074 0104

Serial No.: 10/008,645

Applicant(s): Nemelka STATEMENTE C Filing Date: 9 November 2001 **Confirmation No.: 7296**

Group: 1741

WAR 2 5 2002

SU.S. PATENT DOCUMENTS

Examiner Alnitial	Copy Enclosed	Beument Nather	Date	Name Name	Class	Subclass	Filing Date If Appropriate
Q_	Siterosea	3,387,975	06/11/68	Tamura	T)	
T	-	4,592,816	06/03/86	Emmons et al.			
		4,751,172	06/14/88	Rodriguez et al.			
		4,891,110	01/02/90	Libman et al.			
		5,004,672	04/02/91	D'Ottavio et al.			
		5,196,098	03/23/93	Rodriguez et al.			
		5,205,770	04/27/93	Lowrey et al.			
		5,232,549	08/03/93	Cathey et al.			
		5,459,480	10/17/95	Browning et al.			
		5,466,358	11/14/95	Kiyomiya et al.			
		5,486,126	01/23/96	Cathey et al.			
		5,503,582	04/02/96	Cathey, Jr. et al.			
		5,588,359	12/31/96	Hofmann et al.			
		5,601,751	02/11/97	Watkins et al.			
		5,607,818	03/04/97	Akram et al.			
		5,634,585	06/03/97	Stansbury			Δ
		5,662,831	09/02/97	Chadha			N/A
		5,667,418	09/16/97	Fahlen et al.) 2	
		5,675,212	10/07/97	Schmid et al.			6
		5,931,713	08/03/99	Watkins et al.		7	100
	Х	6,046,539	04/04/00	Haven et al.			90
V	Х	6,153,075	11/28/00	Nemelka			

FOREIGN PATENT DOCUMENTS

Examiner	Сору	Document Number	Date	Country	Class	Subclass	Trans	lation
Initial	Enclosed						Yes	No
		NONE						

Λ	
EXAMINER	Date Considered 3/15/04

^{*}Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

OMB No. 0651-0011 Page 2 of 2

INFORMATION DISCLOSURE STATEMENT

Atty. Docket No.: 153.0634 0104

MAR 2 5 2007

Perial No.: 10/008,645

Group: 1741

nfirmation No.: 7296 Applicant(s): Nemelka

Filing Date: 9 November 2001

OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)

Examiner Copy Initial Enclosed		Document Description					
O _T		Eagle®2005 Developer, Product pamphlet, Shipley Company, Inc. (1991).					
		Eagle®2007 Remover, Product pamphlet, Shipley Company, Inc. (1992).					
		Eagle®2100 ED Photo Resist, Product pamphlet, Shipley Company, Inc. (1992)					
		Jacob, T., et al., "Liquid Resist Allows Land Size Reduction," Electronic Packaging & Production, 36, 27-34 (1996).					
		Miller, P., "Inner-Layer Imaging Using a Novel Electrophoretic Resist," NEPCON EAST 1989 Conference, Boston, MA (1989).					
		Murray, J., "ED Processes Revisted," PC FAB, 22-23 (1992).					
		Shmulovich, J., et al., "Successful Development of Non-Planar Lithography for Micro-Machining Applications," <i>Integrated Photonics Research</i> , 6, 354-357 (1996).					
V		Vidusek, D., "Electrophoretic Photoresist Technology: An Image of the Future - Today," Circuit World, 15, 6-10 (1989).					



	/	Λ	
EXAMINER		1	Date Considered
	0, 1		3/15/04
*Examiner: Initial i	f citation con	sidered whether or not citat	lion is in conformance with MPFP 609. Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

OMB No. 0651-0011

Page 1 of 1

INFORMATION DISCLOSURE STATEMENT

Atty. Docket No.: 150.00730104	Serial No.: 10/008,645
Applicant(s): Jefferson O. Nemelka	Confirmation No.: 7296
Application Filing Date: 9 November 2001	Group: 1741
Information Disclosure Statement mailed:	September 10, 2002

U.S. PATENT DOCUMENTS

Examiner Initial	Copy Enclosed	Document Number	Date	Name	Class	Subclass	Filing Date If
6		5,827,624	10/1998	Stansbury			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Copy Enclosed	Document Number	Date	Country	Class	Subclass	Trans Yes	lation No
		None			\			
			· · · · · · · · · · · · · · · · · · ·					

OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)

Examiner Initial	Copy Enclosed		Document Description
		None	

RECEIVED

SEP 2 0 2002

TC 1700

	<u> </u>			
EXAMINER	// //	^	Date Considered	, , , , , , , , , , , , , , , , , , ,
	e ll		>	15/04
*Examiner: Initial	if citation considere	d, whether or not citation is in c	onformance with MPEP 609:	Draw line through citation if not in

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.